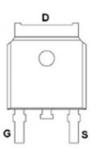


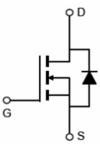
# SMT008N09C1

#### Main Product Characteristics:

V <sub>DSS</sub>	80V				
R <sub>DS</sub> (on)	7.5mΩ(Typ.)				
I <sub>D</sub>	80A				







TO-252 (DPAK)

Pin Assignments

Schematic Diagram

#### **Features and Benefits:**

- Advanced MOSFET process technology
- Special designed for PWM, load switching and general purpose applications
- Ultra low on-resistance with low gate charge
- Fast switching and reverse body recovery
- 150°C operating temperature



### **Description:**

It utilizes the latest processing techniques to achieve the high cell density and reduces the on-resistance with high repetitive avalanche rating. These features combine to make this design an extremely efficient and reliable device for use in power switching application and a wide variety of other applications.

### **Absolute Max Rating:**

Symbol	Parameter	Max.	Units
I <sub>D</sub> @ TC = 25°C	Continuous Drain Current, V <sub>GS</sub> @ 10V①	80	٨
I <sub>DM</sub>	Pulsed Drain Current2	240	A
P <sub>D</sub> @TC = 25°C	Power Dissipation3	130	W
V <sub>DS</sub>	Drain-Source Voltage	80	V
V <sub>GS</sub>	Gate-to-Source Voltage	± 20	V
E <sub>AS</sub>	Single Pulse Avalanche Energy @ L=0.1mH	360	mJ
T <sub>J</sub> T <sub>STG</sub>	Operating Junction and Storage Temperature Range	-55 to +150	°C



## **Thermal Resistance**

Symbol	Characteristics	Тур.	Max.	Units
R <sub>θJC</sub>	Junction-to-case ③	_	1	°C/W
R <sub>0JA</sub>	Junction-to-Ambient		62.5	°C/W

## **Electrical Characterizes** $@T_A=25$ °C unless otherwise specified

Symbol	Parameter	Min.	Тур.	Max.	Units	Conditions	
$V_{(BR)DSS}$	Drain-to-Source breakdown voltage	80	_	_	V	$V_{GS} = 0V, I_D = 250 \mu A$	
R <sub>DS(on)</sub>	Static Drain-to-Source on-resistance	_	7.5	9	mΩ	V <sub>GS</sub> =10V,I <sub>D</sub> =40A	
V <sub>GS(th)</sub>	Gate threshold voltage	2	—	4	V	$V_{DS} = V_{GS}$ , $I_D = 250 \mu A$	
I <sub>DSS</sub>	Drain-to-Source leakage current	_	_	1	μA	$V_{DS} = 80V, V_{GS} = 0V$	
	Coto to Source forward lookage	_	_	100	<b>ب</b> ۸	V <sub>GS</sub> =20V	
I <sub>GSS</sub>	Gate-to-Source forward leakage		_	-100	nA	V <sub>GS</sub> = -20V	
Qg	Total gate charge		95			I <sub>D</sub> = 40A,	
$Q_{gs}$	Gate-to-Source charge	_	18	_	nC	V <sub>DS</sub> =40V,	
$Q_{gd}$	Gate-to-Drain("Miller") charge	_	38	_		$V_{GS} = 10V$	
t <sub>d(on)</sub>	Turn-on delay time	_	25	_		N 4014 M 4014	
t <sub>r</sub>	Rise time		20			V <sub>GS</sub> =10V, V <sub>DS</sub> =40V,	
$t_{d(off)}$	Turn-Off delay time		55	_	ns	$R_{GEN}=3\Omega$	
t <sub>f</sub>	Fall time		22			$R_L=1\Omega$	
C <sub>iss</sub>	Input capacitance		4160			$V_{GS} = 0V$	
Coss	Output capacitance		245		pF	V <sub>DS</sub> = 25V <i>f</i> = 1MHz	
C <sub>rss</sub>	Reverse transfer capacitance	—	180				

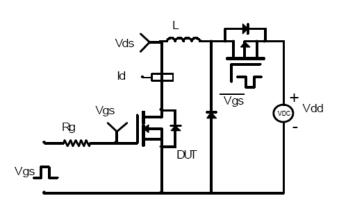
# **Source-Drain Ratings and Characteristics**

Symbol	Parameter	Min.	Тур.	Max.	Units	Conditions	
	Continuous Source Current			80	А	MOSFET symbol	
Is	(Body Diode)					showing the	
I <sub>SM</sub>	Pulsed Source Current		_	240	А	integral reverse	
	(Body Diode)	_				p-n junction diode.	
V <sub>SD</sub>	Diode Forward Voltage	_	—	1.2	V	I <sub>S</sub> =40A, V <sub>GS</sub> =0V	
trr	Reverse Recovery Time	_	8	_	ns	I <sub>S</sub> =20A,di/dt=500A/us	
Qrr	Reverse Recovery Charge	_	35	_	nC	IS=20A,ui/ul=300A/US	

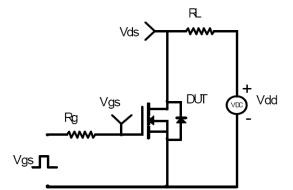


## **Test Circuits and Waveforms**

EAS Test Circuit:

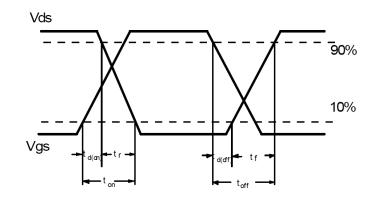


Switching Time Test Circuit:



Switching Waveforms:

**Gate Charge Test Circuit:** 



#### Notes:

①Calculated continuous current based on maximum allowable junction temperature.

- O Repetitive rating; pulse width limited by max. junction temperature.
- ③The power dissipation PD is based on max. junction temperature, using junction-to-case thermal resistance.

(4) The value of  $R_{\theta JA}$  is measured with the device mounted on 1 in 2 FR-4 board with 2oz. Copper, in a still air environment with TA =25  $^\circ C$ 



# SMT008N09C1

## **Typical Electrical and Thermal Characteristics**

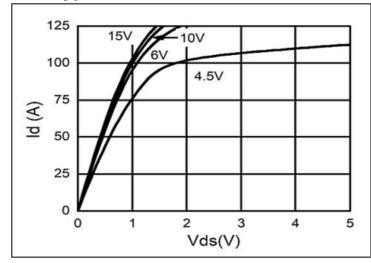


Figure 1: Typical Output Characteristics

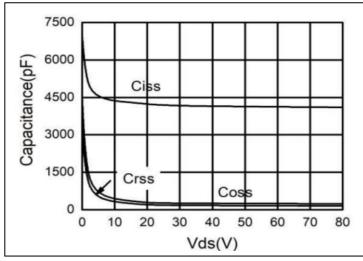


Figure 3: Typical Capacitance

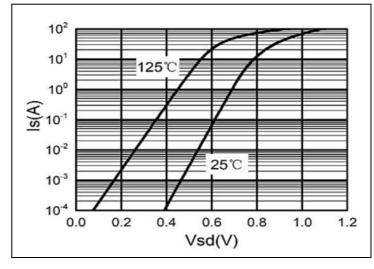


Figure 5: Body Diode Characteristics

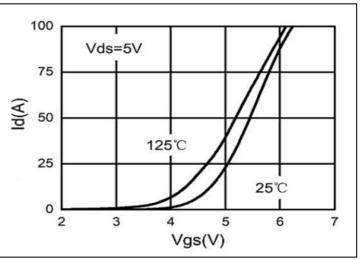


Figure 2: Typical Transfer Characteristics

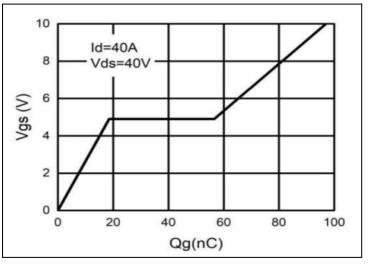


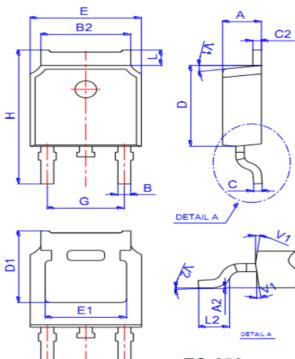
Figure 4: Typical Gate Charge





### **Mechanical Data:**

TO-252 Package Outline(Unit:mm)



	Dimensions							
Ref.	I	Millimeter	rs	Inches				
	Min.	Тур.	Max.	Min.	Тур.	Max.		
Α	2.10		2.50	0.083		0.098		
A2	0		0.10	0		0.004		
В	0.66		0.86	0.026		0.034		
B2	5.18		5.48	0.202		0.216		
С	0.40		0.60	0.016		0.024		
C2	0.44		0.58	0.017		0.023		
D	5.90		6.30	0.232		0.248		
D1		5.30REF		0.209REF				
E	6.40		6.80	0.252		0.268		
E1	4.63			0.182				
G	4.47		4.67	0.176		0.184		
н	9.50		10.70	0.374		0.421		
L	1.09		1.21	0.043		0.048		
L2	1.35		1.65	0.053		0.065		
V1		<b>7</b> °			7°			
V2	0°		6°	0°		6°		

TO-252





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